

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2	((test testing tests tester tested) same (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) same (expected estimated) same (IC semiconductor circuit semiconductors circuits processor processors microprocessor microprocessors micro-processor micro-processors LUT DUT CUT)) and ((instruction instructions executable pattern vector (test adj (data vector))) with (test testing tests tester tested)) and (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) and (expected estimated) and ((compare compared compares comparing comparison comparator) with (expected)) and statistical same coverage	USPAT	OR	ON	2005/03/26 16:49
S4	1	"870121".ap. and Mathieu.in.	US-PGPUB	OR	ON	2005/03/26 13:01
S5	762	(test testing tests tester tested) same (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) same (expected estimated) same (IC semiconductor circuit semiconductors circuits processor processors microprocessor microprocessors micro-processor micro-processors LUT DUT CUT)	USPAT	OR	ON	2005/03/26 09:31
S6	492	(test testing tests tester tested) same (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) same (expected estimated) same (IC semiconductor circuit semiconductors circuits processor processors microprocessor microprocessors micro-processor micro-processors LUT DUT CUT) and ((instruction instructions executable pattern vector (test adj (data vector))) with (test testing tests tester tested))	USPAT	OR	ON	2005/03/26 09:35

S7	492	((test testing tests tester tested) same (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) same (expected estimated) same (IC semiconductor circuit semiconductors circuits processor processors microprocessor microprocessors micro-processor micro-processors LUT DUT CUT)) and ((instruction instructions executable pattern vector (test adj (data vector))) with (test testing tests tester tested)) and (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) and (expected estimated)	USPAT	OR	ON	2005/03/26 11:09
S8	266	((test testing tests tester tested) same (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) same (expected estimated) same (IC semiconductor circuit semiconductors circuits processor processors microprocessor microprocessors micro-processor micro-processors LUT DUT CUT)) and ((instruction instructions executable pattern vector (test adj (data vector))) with (test testing tests tester tested)) and (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) and (expected estimated) and ((compare compared compares comparing comparison comparator) with (expected))	USPAT	OR	ON	2005/03/26 16:49

S9	118	((test testing tests tester tested) same (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) same (expected estimated) same (IC semiconductor circuit semiconductors circuits processor processors microprocessor microprocessors micro-processor micro-processors LUT DUT CUT)) and ((instruction instructions executable pattern vector (test adj (data vector))) with (test testing tests tester tested)) and (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) and (expected estimated) and ((compare compared compares comparing comparison comparator) with (expected)) and ((test testing tests tester tested) with (processor processors microprocessor microprocessors micro-processor micro-processors))	USPAT	OR	ON	2005/03/26 11:36
S10	40	((test testing tests tester tested) same (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) same (expected estimated) same (IC semiconductor circuit semiconductors circuits processor processors microprocessor microprocessors micro-processor micro-processors LUT DUT CUT)) and ((instruction instructions executable pattern vector (test adj (data vector))) with (test testing tests tester tested)) and (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) and (expected estimated) and ((compare compared compares comparing comparison comparator) with (expected)) and (self adj test)	USPAT	OR	ON	2005/03/26 11:37

S11	22	((test testing tests tester tested) same (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) same (expected estimated) same (IC semiconductor circuit semiconductors circuits processor processors microprocessor microprocessors micro-processor micro-processors LUT DUT CUT)) and ((instruction instructions executable pattern vector (test adj (data vector))) with (test testing tests tester tested)) and (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) and (expected estimated) and ((compare compared compares comparing comparison comparator) with (expected)) and ((test testing tests tester tested) with (processor processors microprocessor microprocessors micro-processor micro-processors)) and (self adj test)	USPAT	OR	ON	2005/03/26 12:17
S12	4	(behavioral adj model) and ((instruction instructions executable pattern vector (test adj (data vector))) with (test testing tests tester tested)) and ((test testing tests tester tested) with (processor processors microprocessor microprocessors micro-processor micro-processors)) and (self adj test)	USPAT	OR	ON	2005/03/26 12:17
S13	4	("5978260"   "6148277"   "6216252"   "6285974").PN. OR ("6813201").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/03/26 12:24
S14	1433	714/741;703/14-17.ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2005/03/26 12:26
S15	131	714/741;703/14-17.ccls. and (test testing tests tester tested) same (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) same (expected estimated) same (IC semiconductor circuit semiconductors circuits processor processors microprocessor microprocessors micro-processor micro-processors LUT DUT CUT)	US-PGPUB; USPAT; USOCR	OR	ON	2005/03/26 12:26

S16	99	714/741;703/14-17.ccls. and (test testing tests tester tested) same (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) same (expected estimated) same (IC semiconductor circuit semiconductors circuits processor processors microprocessor microprocessors micro-processor micro-processors LUT DUT CUT)	USPAT	OR	ON	2005/03/26 12:37
S17	12	714/741;703/14-17.ccls. and ((test testing tests tester tested) with (processor processors microprocessor microprocessors micro-processor micro-processors)) and (self adj test)	USPAT	OR	ON	2005/03/26 12:40
S18	7	714/741;703/14-17.ccls. and ((test testing tests tester tested) with (processor processors microprocessor microprocessors micro-processor micro-processors)) and (self adj test) and ((compare compared compares comparing comparison comparator) with (expected))	USPAT	OR	ON	2005/03/26 12:45
S19	7	714/741;703/14-17.ccls. and ((test testing tests tester tested) with (processor processors microprocessor microprocessors micro-processor micro-processors)) and (self adj test) and ((compare compared compares comparing comparison comparator) with (expected)) and (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator)	USPAT	OR	ON	2005/03/26 12:45
S20	2	("4918378"   "5617531").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/03/26 12:47

S21	285	("3622762"   "3749897"   "3919637"   "4161276"   "4176780"   "4263651"   "4315315"   "4392226"   "4410938"   "4455619"   "4590581"   "4594685"   "4594711"   "4625310"   "4635218"   "4635258"   "4718065"   "4722071"   "4745355"   "4754215"   "4758953"   "4772948"   "4780755"   "4782487"   "4801870"   "4802133"   "4809170"   "4813013"   "4817018"   "4817093"   "4821266"   "4831524"   "4847785"   "4849880"   "4853928"   "4862399"   "4868770"   "4870346"   "4872169"   "4881179"   "4885683"   "4901221"   "4903199"   "4918594"   "4922432"   "4945536"   "4965741"   "4970664"   "5005119"   "5034899"   "5051938"   "5111413"   "5185745"   "5185882"   "5195096"   "5197070"   "5210861"   "5245543"   "5270642"   "5281864"   "5305327"   "5321825"   "5396170"   "5442763"   "5459836"   "5471480"   "5497458"   "5513344"   "5515501"   "5535223"   "5539680"   "5539878"   "5555249"   "5566319"   "5570375"   "5592493"   "5615373"   "5634037"   "5684808"   "5696772"   "5796946"   "5862152"   "5974241"   "5974248"   "5983381"   "5995740"   "6028983"   "6047247"   "6106568"   "6158032"   "Re34445").PN. OR ("4727549"   "5202889"   "5331570"   "5371851"   "5377122"   "5517637"   "5680544"   "6285974"   "6304837"   "6427217"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/03/26 12:49
S22	3	S21 and ((test testing tests tester tested) with (processor processors microprocessor microprocessors micro-processor micro-processors)) and (self adj test) and ((compare compared compares comparing comparison comparator) with (expected)) and (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator)	US-PGPUB; USPAT; USOCR	OR	ON	2005/03/26 12:49
S23	1	"870121".ap. and Mathieu.in. and instruction	US-PGPUB	OR	ON	2005/03/26 13:28
S24	301	714/38.ccls.	US-PGPUB	OR	ON	2005/03/26 13:04

S25	1	714/38.ccls. and (self adj test) and ((compare compared compares comparing comparison comparator) with (expected)) and (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator)	US-PGPUB	OR	ON	2005/03/26 13:04
S26	3	714/38.ccls. and (self adj test) and ((compare compared compares comparing comparison comparator) with (expected)) and (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator)	USPAT	OR	ON	2005/03/26 13:06
S27	41	714/38.ccls. and ((compare compared compares comparing comparison comparator) with (expected)) and (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator)	USPAT	OR	ON	2005/03/26 13:39
S28	0	"870121".ap. and Mathieu.in. and instruction and ((instruction instructions) adj to adj be adj tested)	US-PGPUB	OR	ON	2005/03/26 13:30
S29	1	"870121".ap. and Mathieu.in. and instruction and ((instruction instructions) adj3 tested)	US-PGPUB	OR	ON	2005/03/26 13:30
S30	101	((((test testing tests tester tested) with (processor processors microprocessor microprocessors micro-processor micro-processors)).ab. ((test testing tests tester tested) with (processor processors microprocessor microprocessors micro-processor micro-processors)).ti.) and ((compare compared compares comparing comparison comparator) with (expected)) and (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator)	USPAT	OR	ON	2005/03/26 13:41

S31	6	((test testing tests tester tested) with (processor processors microprocessor microprocessors micro-processor micro-processors)).ab. ((test testing tests tester tested) with (processor processors microprocessor microprocessors micro-processor micro-processors)).ti.) and ((compare compared compares comparing comparison comparator) with (expected)) and (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator) and ((model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator).ab. and (model simulate simulated simulating simulates simulation simulator emulate emulates emulated emulating emulation emulator).ti.)	USPAT	OR	ON	2005/03/26 15:26
S32	434	326/16.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/26 14:34
S33	1	"5377122".pn.	USPAT	OR	ON	2005/03/26 15:36
S34	1	"5377122".pn. and user	USPAT	OR	ON	2005/03/26 15:36